Impact of in-situ controlled disorder screening on fractional quantum Hall effects and composite-fermion transport

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We examine the impact of random potential due to remote impurites (RIs) and its in-situ controlled screening on fractional quantum Hall effects (FQHEs) around Landau-level filling factor $v = 1/2$. The experiment is made possible by using a dual-gate GaAs quantum well (QW) that allows for the independent control of the density n_e of the two-dimensional electron system in the QW and that (n_{SL}) of excess electrons in the modulationdoping superlattice. As the screening is reduced by decreasing n_{SL} at a fixed n_e , we observe a decrease in the apparent energy gap of the FQHEs deduced from thermal activation, which signifies a corresponding increase in the disorder broadening Γ of composite fermions (CFs). Interestingly, the increase in Γ is accompanied by a noticeable increase in the longitudinal resistivity at $v = 1/2$ ($\rho_{1/2}$), with a much stronger correlation with Γ than electron mobility μ has. The in-situ control of RI screening enables us to disentangle the contributions of RIs and background impurities (BIs) to $\rho_{1/2}$, with the latter in good agreement with the CF theory. We construct a scaling plot that helps in estimating the BI contribution to $\rho_{1/2}$ for a given set of n_e and μ .

The fractional quantum Hall effect (FQHE) [\[1](#page-3-0)] that clean two-dimensional electron systems (2DESs) exhibit in a strong perpendicular magnetic field (*B*) at low temperatures is a quintessential example of many-body topological phase and is thus attracting interest for the rich physics contained [\[2](#page-3-1)[–4](#page-3-2)] and also as a building block for fault-tolerant topological quantum computation [\[5](#page-3-3), [6](#page-3-4)]. FQHEs can be understood, both intuitively and quantitatively, by the composite-fermion (CF) theory [\[7\]](#page-3-5), which maps FQHEs to integer quantum Hall effects of a CF, an electron with an even number of flux quanta attached. The theory explains in a clear way the Landau-level filling factor $v = hn_e/eB$) at which FQHEs develop around $v = 1/2$ and their relative strength [\[8](#page-3-6), [9\]](#page-3-7) (*h* is Planck's constant, *n^e* is the electron density, and *e* is the elementary charge). At the same time, the CF model maps the system of strongly interacting electrons at $v = 1/2$ to that of weakly interacting CFs at zero effective magnetic field, providing a theoretical framework to study the scattering of CFs and calculate the resistivity at $v = 1/2$ [\[10\]](#page-3-8).

While FQHEs have been observed in various material systems [\[11](#page-4-0)[–28\]](#page-4-1), GaAs remains the platform where the cleanest 2DESs can be materialized [\[29](#page-4-2)[–31\]](#page-4-3). In typical 2DESs formed in modulation-doped GaAs/AlGaAs heterostructures or quantum wells (QWs), two main scattering sources limit electron mobility μ : background ionized impurities and remote ionized impurities, the latter introduced by modulation doping [\[32\]](#page-4-4). As GaAs samples used for FQHE studies generally have thick spacer layers, which separate the 2DES from remote impurities (RIs), μ primarily reflects the background impurity (BI) concentration and has been used as the quality indicator of 2DESs. However, recent studies have shown that, in addition to improving μ by reducing BIs, properly screening the random potentials arising from RIs is mandatory for observing fragile FQHEs with a small energy gap [\[30](#page-4-5), [33](#page-4-6)]. Superlattice (SL) doping [\[34](#page-4-7), [35\]](#page-4-8), with Si donors incorporated in a narrow GaAs layer flanked by thin AlAs layers, is an effective way to implement this. Some of the doped electrons occupy the *X* valleys of AlAs, where these "excess"

electrons remain mobile and screen the RI potential without causing unwanted parallel conduction [\[36,](#page-4-9) [37](#page-4-10)]. Recently, we demonstrated the effect of RI screening on μ by controlling the excess electron density in-situ using a gate [\[38](#page-4-11)]. This suggests that the same technique can be used to study the impact of RI screening on FQHEs and CF transport.

In this paper, we study the impact of disorder and its screening on FQHEs in a GaAs 2DES by controlling in-situ the strength of RI screening. We measure the energy gap $\Delta_{\rm v}$ of several FQHEs at $v = p/(2p \pm 1)$ (*p* is an integer) around $v = 1/2$ and the resistivity at $v = 1/2$ ($\rho_{1/2}$) under different screening conditions. We observe that $\rho_{1/2}$ as well as $\Delta_{\rm v}$ vary with the degree of screening. We extract the disorder broadening Γ of CFs from the measured Δ_{ν} and find that it is much more strongly correlated with $\rho_{1/2}$ than 2DES mobility μ is, indicating that the former is a better quality indicator for FQHEs. With the in-situ control of RI screening, we are able to disentangle the contributions of RIs and BIs to $\rho_{1/2}$. We use the CF theory to calculate the contribution of BIs to $\rho_{1/2}$ to find a good agreement with experiment. Based on these results, we construct a scaling plot, which allows one to estimate the contribution of BIs to $\rho_{1/2}$.

The sample consists of a 30-nm-wide GaAs QW sandwiched between Al_{0.27}Ga_{0.73}As barriers, grown on an *n*type GaAs (001) substrate. The QW, with its center located 207 nm below the surface, is modulation-doped on one side, with Si δ -doping ($N_{\text{Si}} = 1 \times 10^{16} \text{ m}^{-2}$) at the center of the AlAs/GaAs/AlAs (2 nm/3 nm/2 nm) SL located 75 nm above the OW. The wafer was processed into a 100 - μ m-wide Hall bar with voltage probe distance of $120 \mu m$ and fitted with a Ti/Au front gate. The *n*-type substrate was used as a back gate. We measured FQHEs under different degrees of disorder screening by first setting the front-gate voltage (V_{FG}) at 4.3 K and waiting long enough for n_e to stabilize before cooling the sample to 0.27 K. After the sample had cooled, we applied a back-gate voltage to adjust n_e to the desired value. We use the quantity $f_{\rm sc} = n_{\rm SL}/N_{\rm Si}$ as the parameter representing the degree of screening. Since n_{SL} is not directly measurable, we

FIG. 1. R_{xx} vs. v^{-1} at fixed density $n_e = 1.2 \times 10^{15}$ m⁻² with different V_{FG} at 0.27 K. *B* was swept from 0 to 15 T. Red, black, and blue traces were taken under strong, intermediate, and weak screening conditions, respectively. Inset: *V*_{FG} dependence of screening effect defined by $f_{\text{sc}} = n_{\text{SL}}/N_{\text{Si}}$.

estimated n_{SL} and hence f_{sc} by analyzing the V_{FG} dependence of n_e at 1.6 K. The estimated f_{sc} varies almost linearly with *V*FG, as shown in the inset of Fig. [1.](#page-1-0) More details of the estimation of $f_{\rm sc}$ are described in Ref. [\[38\]](#page-4-11).

Figure [1](#page-1-0) shows the longitudinal resistance R_{xx} measured at a fixed density of $n_e = 1.2 \times 10^{15} \text{ m}^{-2}$ with $V_{\text{FG}} = -0.8, -1.1$, and −1.3 V, corresponding to strong, intermediate, and weak screening $(f_{\text{sc}} = 0.42, 0.24, \text{and } 0.13)$, respectively, plotted as a function of v^{-1} . The FQHEs at $v = 1/3$ and $2/3$ are nearly fully developed under all conditions. On the other hand, those at $v = 2/5$, $3/5$, $3/7$, and $4/7$ clearly become weaker as V_{FG} is lowered, and hence the screening is reduced. In addition, the dip at $v = 4/9$, which is visible under the strong screening condition, disappears under the weak screening condition. Around $v = 3/2$, similar *V*_{FG} dependence is seen for FQHEs at $v = 4/3$ and $5/3$.

To characterize the impact of the screening on FQHEs quantitatively, we measured the temperature (*T*) dependence of R_{xx} and deduced the energy gap Δ_v . Figure [2\(](#page-1-1)a) plots ln(R_{xx}) vs 1/*T* at $v = 1/3$ and 2/5, corresponding to $p = 1$ and 2, measured under three different screening conditions. We obtain $\Delta_{\rm v}$ by fitting the data in the temperature range where the activated behavior is seen with $R_{xx} \propto \exp(-\Delta_v/2T)$. In the same way, we also estimated $\Delta_{\rm V}$ for FQHEs at $v = 2/3$, 3/5, 4/7, and 3/7 (corresponding to *p* = −2, −3, −4, and 3, respectively) under different screening conditions. To systematically analyze the obtained $\Delta_{\rm V}$ for different *p*'s, we used the scaling law introduced in Ref. [\[9\]](#page-3-7):

$$
\Delta_{\mathsf{V}} = \frac{\kappa}{|2p+1|} \frac{e^2}{4\pi\varepsilon\ell_B} - \Gamma \tag{1}
$$

where $\varepsilon = \varepsilon_r \varepsilon_0$ with ε_0 the vacuum permittivity and $\varepsilon_r = 13$ for (Al)GaAs, $\ell_B = (\hbar/eB)^{1/2}$ is the magnetic length with

FIG. 2. (a) Arrhenius plot for R_{xx} at $v = 1/3$ (filled circles) and $2/5$ (open circles) under different screening conditions. (b) Scaling of activation energy for FQHEs around $v = 1/2$ under different screening conditions, deduced from the Arrhenius plot. The solid lines represent fits using Eq. (1). The magnitude of the negative intercept of these lines with the *y* axis gives Γ. (c) Γ obtained from the scaling law fitting, plotted as a function of f_{sc} .

 $\hbar = h/2\pi$, κ is a dimensionless parameter representing the strength of the Coulomb interaction, and Γ denotes the gap reduction due to disorder. By plotting Δ ^{*v*}'s for different *p*'s as a function of $(e^2/4\pi\varepsilon\ell_B)/(2p+1)$ [Fig. [2\(](#page-1-1)b)] and fitting them using Eq. (1), κ and Γ are obtained from the slope and intercept, respectively. The data for the weak and strong screening can be fitted using the same κ value (= 0.197 \pm 0.007), indicating that the excess electrons in the SL do not discernibly affect the strength of the intralayer Coulomb interaction responsible for the FQHEs. In contrast, the impact on Γ is obvious—Γ decreasing upon increasing screening. Measurements for various $f_{\rm sc}$ values, summarized in Fig. [2\(](#page-1-1)c), reveal that Γ increases from 3.6 to 5.8 K as f_{sc} decreases from 0.55 to 0.13. As Γ can be viewed as representing the Landau-level broadening for CFs, these results confirm that the in-situ control of the visibility of the FQHEs demonstrated in Fig. [1\(](#page-1-0)a) is due to the controlled screening of disorder.

Another important observation in Fig. [1](#page-1-0) is that, with decreasing f_{sc} , R_{xx} increases not only in the FQHE regions but also in regions between them. We focus on the state at $v = 1/2$ and plot $\rho_{1/2}$ as a function of $f_{\rm sc}$ in Fig. [3\(](#page-2-0)a). $\rho_{1/2}$ increases noticeably with decreasing $f_{\rm sc}$ below 0.42 ($V_{\rm FG} < -0.8$ V), whereas it is almost constant for $f_{\rm sc} \geq 0.42$. Similar $f_{\rm sc}$ dependences are observed for other half-integer fillings $v = 3/2$, $5/2$, and $7/2$ [inset of Fig. [3\(](#page-2-0)a)]. To examine the correlation between FQHEs and CF transport, we plot Γ versus $\rho_{1/2}$ in Fig. [3\(](#page-2-0)b). Their relation can be fitted approximately by $\Gamma \propto \rho_{1/2}^{0.5}$ as shown by the solid line. For comparison, we plot Γ against $ρ_0$, the resistivity at zero magnetic field, a quantity directly related to μ (= 1/*en*_{*e*} ρ_0) [inset of Fig. [3\(](#page-2-0)b)]. When Γ varies by 38%, ρ_0 only changes by 13% ($\mu = 191-$

FIG. 3. (a) $\rho_{1/2}$ under different screening conditions at $n_e = 1.2 \times$ 10¹⁵ m−² . The dashed line shows the contribution of BI scattering to $\rho_{1/2}$ calculated using Eq. (2) modified for BIs. Inset: Resistivity at $v = 3/2$, 5/2, and 7/2 under different screening conditions. (b) Plots of Γ with respect to $\rho_{1/2}$ under different screening conditions. The solid line indicates as a guide the fitting using the $(\rho_{1/2})^{0.5}$ function. Inset: Plots of Γ with respect to the zero field resistivity ρ_0 .

219 m²/Vs), whereas $\rho_{1/2}$ changes by 51% for the same Γ range, demonstrating that $\rho_{1/2}$ is more strongly correlated with the visibility of FQHEs. This result bears an intriguing similarity with the recent report that the resistivity at $v = 5/2$ in the high-temperatures regime serves as an indicator of the strength of the $v = 5/2$ FQHE that emerges at low temperatures [\[39](#page-4-12)].

Now we discuss the scattering mechanism that determines $\rho_{1/2}$. In the CF model, at $v = 1/2$ CFs experience a zero effective magnetic field in the mean field and form a Fermi surface. According to Ref. [\[10](#page-3-8)], scattering of CFs at $v = 1/2$ is dominated by fluctuations in the electron density induced by the charged impurities randomly distributed in the modulationdoped layer, which translate into fluctuations in the Chern-Simons gauge field and act as random magnetic fields with zero mean. The $\rho_{1/2}$ due to this scattering mechanism is given by $[10]$

$$
\rho_{1/2} = \frac{n_{\rm imp}}{n_e} \frac{1}{k_F d_s} \frac{4\pi\hbar}{e^2},
$$
\n(2)

where n_{imp} is the sheet density of the ionized impurities, $k_F =$ $(4\pi n_e)^{1/2}$ is the Fermi wave number of spin-polarized CFs, and *d^s* is the distance between the 2DES and the doped layer. In the ideal case of no BIs or charge traps, we have $n_{\text{imp}} = n_e$, where $\rho_{1/2}$ takes a minimum value determined solely by the factor $k_F d_s (= d_s/\ell_B$ at $v = 1/2$).

In our sample, the density of excess electrons in the SL doping layer can be varied via V_{FG} . This can be thought of as effectively varying n_{imp} in Eq. (2), which enables us to disentangle the contribution of RIs to $\rho_{1/2}$ from other ones. In Fig. [3\(](#page-2-0)a), $\rho_{1/2}$ first decreases with increasing $f_{\rm sc}$ and then becomes almost constant for $f_{\rm sc} > 0.4$. Thus, we can clearly identify the increase in $\rho_{1/2}$ at $f_{\rm sc}$ < 0.4 as due to RI scattering. On the other hand, this suggests that at $f_{\rm sc} > 0.4$ the screening is sufficient to make the contribution of RIs insignificant. To examine the mechanism that determines $\rho_{1/2}$ in this well-screened regime, we estimated the contribution of BIs by modifying Eq. (2). We replaced n_{imp} and d_s in Eq. (2) with $n_{\text{BI}}(z)dz$, the sheet density of BIs within a slice dz at each position *z* along the growth direction, and $\langle d(z) \rangle$, the expectation value of the distance from that position to the 2DES, respectively, and integrated Eq. (2) over *z* [\[40](#page-4-13)]. A calculation using a constant n_{BI} of $1.7 \times 10^{14} \text{ cm}^{-3}$, deduced from the analysis of mobility, gives $\rho_{1/2} = 0.56 \text{ k}\Omega/\square$ [shown by the horizontal dashed line in Fig. 3(a)], which accounts for the $\rho_{1/2}$ values at $f_{\rm sc} > 0.4$ surprisingly well.

Next, we quantitatively investigate the contribution of RIs to $\rho_{1/2}$ and the impact of controlled screening therein. We examined the n_e dependence of $\rho_{1/2}$ by varying n_e with the back gate at a fixed *V*_{FG}. Note that the back gate barely affects n_{SL} , which ensures that the screening condition remains nearly constant upon varying n_e . The results for $V_{\text{FG}} = -1.2$ and −0.6 V, which correspond to the weak (f_{sc} = 0.18) and strong $(f_{\rm sc} = 0.55)$ screening, respectively, are shown in Fig. [4\(](#page-3-9)a). The solid line indicates the calculated $\rho_{1/2}$ due to BI scattering, assuming the same n_{BI} as above. The calculation well accounts for the data for $f_{\rm sc} = 0.55$, consistent with the expected $n_e^{-3/2}$ dependence, which corroborates that in our sample $\rho_{1/2}$ in the well-screened regime is dominated by BI scattering. On the other hand, we are able to unambiguously ascribe the difference between the $\rho_{1/2}$ values for $f_{\rm sc} = 0.18$ and 0.55 to RI scattering. We find that the difference can be well fitted by Eq. (2) . Taking d_s to be the center-to-center distance 90 nm between the QW and the doping SL, we obtain $n_{\text{imp}} = 1.0 \times 10^{14} \text{ m}^{-2}$ from the fit. We note that this is only 2.7% that of the difference in the remote ionized impurity density if we simply evaluate it as $N_{\text{Si}} - n_{\text{SL}} = (1 - f_{\text{sc}})N_{\text{Si}}$. Although it is known that Eq. (2) tends to overestimate $\rho_{1/2}$ compared to experimental values for high-quality 2DESs [\[41\]](#page-4-14) (e.g., by a factor of \sim 3 [\[8,](#page-3-6) [10\]](#page-3-8)), the above reduction factor of 2.7% is much more significant. It indicates that the screening by the excess electrons is effective even in the weak screening case, making the simple analysis regarding RIs as an ensemble of unscreened charges inadequate, similarly to what has been reported for 2DES mobility [\[36](#page-4-9)[–38\]](#page-4-11).

FIG. 4. (a) n_e dependence of $\rho_{1/2}$. Red and blue symbols are data taken under strong and weak screening conditions, respectively. The solid curve is a calculation of BI contribution to $\rho_{1/2}$. (b) Scaling plot of CF and 2DES mobilities normalized by $n_e^{0.5}$ and n_e , respectively. Circles are replots of the data in (a) taken under strong (red) and weak (blue) screening conditions. As a reference, other reported values are also plotted (diamonds). The solid, dashed, and dotted lines are the calculation results for $n_e = 1.0, 2.0,$ and 3.0×10^{15} m⁻², respectively, obtained with varying n_{BI} .

Finally, we examine the relation between CF mobility $\mu_{CF} = 1/en_e\rho_{1/2}$ and 2DES mobility μ . As we have shown, μ _{CF} is governed by both RIs and BIs, whereas in typical highmobility GaAs 2DESs with large d_s , μ is governed mostly by BIs $[32]$. This suggests that one can take μ as a measure of n_{BI} and use this n_{BI} to estimate μ_{CF} limited by BIs. Then, deviation of measured μ_{CF} from this value can be ascribed to RI scattering. To do this at one go for different densities, we construct a scaling plot as follows. As $k_F \propto n_e^{1/2}$ in Eq. (2), we have $\rho_{1/2} \propto n_e^{-3/2}$ and hence $\mu_{\rm CF} \propto n_e^{1/2}$. For GaAs 2DESs, it is known that the approximate relation $\mu \propto n_e^{\alpha}$ holds for BIlimited mobility, with $\alpha \approx 1$ for $n_e = 1 - 2 \times 10^{15}$ m⁻² [\[32](#page-4-4)]. We therefore make a plot of $\mu_{\rm CF}/n_e^{1/2}$ versus μ/n_e as shown in Fig. $4(b)$ $4(b)$, where we plot the experimental data in Fig. $4(a)$ together with calculations for several densities obtained with varying n_{BI} . Data in the literature for GaAs 2DESs with conventional modulation doping, with both $\rho_{1/2}$ and μ available [\[42](#page-4-15)[–44\]](#page-5-0), are also plotted for comparison. Due to the scaling, the calculated curves for different densities are placed close to each other. Similarly, our data for various *n^s* concentrate around two points for the weak and strong screening. We observe that all the experimental data lie below the calculated curves, which suggests the influence of RI scattering. Among all the data plotted here, our data for the strong screening lie closest to the calculated curves, indicating efficient screening of RIs. This is reasonable, as the samples in the literature employed conventional modulation doping. It would therefore be interesting to add data for recent ultrahigh-quality samples with SL doping [\[31\]](#page-4-3) to this plot, which will be possible if $\rho_{1/2}$ is available. We believe that our analysis and the basic idea of the scaling plot are helpful in identifying the mechanisms limiting the visibility of FQHEs and improving sample design and growth of various materials not limited to modulationdoped GaAs QWs or heterostructures.

In summary, we investigated the impact of in-situ controlled disorder screening on FQHEs. We found that the screening of RIs impacts not only the visibility of the FQHEs but also $\rho_{1/2}$, the resistivity at $v = 1/2$, or CF mobility. In the wellscreened regime, the measured $\rho_{1/2}$ agrees well with that due to BIs estimated using the CF theory. The strong correlation between the strength of FQHEs and $\rho_{1/2}$ proves $\rho_{1/2}$, or CF mobility, to be a better quality indicator for FQHEs than 2DES mobility.

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- [1] D. C. Tsui, H. L. Stormer, and A. C. Gossard, "Twodimensional magnetotransport in the extreme quantum limit," [Physical Review Letters](http://dx.doi.org/ 10.1103/PhysRevLett.48.1559) 48, 1559–1562 (1982).
- [2] Gregory Moore and Nicholas Read, "Nonabelions in the fractional quantum Hall effect," [Nuclear Physics B](http://dx.doi.org/ https://doi.org/10.1016/0550-3213(91)90407-O) 360, 362–396 (1991).
- [3] Xiao-Gang Wen, "Topological orders and edge excitations in fractional quantum Hall states," [Advances in Physics](https://doi.org/10.1080/00018739500101566) 44, 405–473 (1995).
- [4] D. E. Feldman and Bertrand I. Halperin, "Fractional charge and fractional statistics in the quantum Hall effects," [Reports on Progress in Physics](https://arxiv.org/abs/2102.08998v2) 84 (2021).
- [5] C. Nayak, S. H. Simon, A. Stern, M. Freedman, and S. Das Sarma, "Non-abelian anyons and topological quantum computation," Rev. Mod. Phys. 80[, 1083–1159 \(2008\).](http://dx.doi.org/10.1103/RevModPhys.80.1083)
- [6] R. S. K. Mong, D. J. Clarke, J. Alicea, N. H. Lindner, P. Fendley, C. Nayak, Y. Oreg, A. Stern, E. Berg, K. Shtengel, and M. P. A. Fisher, "Universal Topological Quantum Computation from a Superconductor-Abelian Quantum Hall Heterostructure," Phys. Rev. X 4[, 011036 \(2014\).](http://dx.doi.org/10.1103/PhysRevX.4.011036)
- [7] J. K. Jain, "Composite-fermion approach for the fractional quantum Hall effect," Phys. Rev. Lett. 63[, 199–202 \(1989\).](http://dx.doi.org/ 10.1103/PhysRevLett.63.199)
- [8] R. R. Du, H. L. Stormer, D. C. Tsui, L. N. Pfeiffer, and K. W. West, "Experimental evidence for new particles in the fractional quantum Hall effect," Phys. Rev. Lett. 70[, 2944–2947 \(1993\).](http://dx.doi.org/ 10.1103/PhysRevLett.70.2944)
- [9] H. C. Manoharan, M. Shayegan, and S. J. Klepper, "Signatures of a Novel Fermi Liquid in a Two-Dimensional Composite Particle Metal," Phys. Rev. Lett. 73[, 3270–3273 \(1994\).](http://dx.doi.org/ 10.1103/PhysRevLett.73.3270)
- [10] B. I. Halperin, P. A. Lee, and N. Read, "Theory of the halffilled Landau level," Phys. Rev. B 47[, 7312–7343 \(1993\).](http://dx.doi.org/10.1103/PhysRevB.47.7312)
- [11] E. P. De Poortere, Y. P. Shkolnikov, E. Tutuc, S. J. Papadakis, M. Shayegan, E. Palm, and T. Murphy, "Enhanced electron mobility and high order fractional quantum hall states in alas quantum wells," Appl.Phys. Lett. 80[, 1583–1585 \(2002\).](http://dx.doi.org/ 10.1063/1.1456265)
- [12] Yoon Jang Chung, K. A. Villegas Rosales, H. Deng, K. W. Baldwin, K. W. West, M. Shayegan, and L. N. Pfeiffer, "Multivalley two-dimensional electron system in an AlAs quantum well with mobility exceeding 2×10^6 cm²V⁻¹s⁻¹," [Phys. Rev. Materials](http://dx.doi.org/10.1103/PhysRevMaterials.2.071001) 2, 071001(R) (2018).
- [13] K. Lai, W. Pan, D. C. Tsui, and Ya-Hong Xie, "Fractional quantum Hall effect at $v = \frac{2}{3}$ and $\frac{4}{3}$ in strained Si quantum wells," Phys. Rev. B 69[, 125337 \(2004\).](http://dx.doi.org/10.1103/PhysRevB.69.125337)
- [14] Xu Du, Ivan Skachko, Fabian Duerr, Adina Luican, and Eva Y Andrei, "Fractional quantum Hall effect and insulating phase of Dirac electrons in graphene," Nature 462[, 192–195 \(2009\).](http://dx.doi.org/ 10.1038/nature08522)
- [15] K. I. Bolotin, F. Ghahari, M. D. Shulman, H. L. Stormer, and P. Kim, "Observation of the fractional quantum Hall effect in graphene," Nature 462[, 196–199 \(2009\).](http://dx.doi.org/10.1038/nature08582)
- [16] C. R. Dean, A. F. Young, P. Cadden-Zimansky, L. Wang, H. Ren, K. Watanabe, T. Taniguchi, P. Kim, J. Hone, and K. L. Shepard, "Multicomponent fractional quantum Hall effect in graphene," Nature Physics 7[, 693–696 \(2011\).](http://dx.doi.org/ 10.1038/nphys2007)
- [17] H. Polshyn, H. Zhou, E. M. Spanton, T. Taniguchi, K. Watanabe, and A. F. Young, "Quantitative Transport Measurements of Fractional Quantum Hall Energy Gaps in Edgeless Graphene Devices," Phys. Rev. Lett. 121[, 226801 \(2018\).](http://dx.doi.org/ 10.1103/PhysRevLett.121.226801)
- [18] Y. Zeng, J. I. A. Li, S. A. Dietrich, O. M. Ghosh, K. Watanabe, T. Taniguchi, J. Hone, and C. R. Dean, "High-quality magnetotransport in graphene using the edge-free corbino geometry," Phys. Rev. Lett. 122[, 137701 \(2019\).](http://dx.doi.org/ 10.1103/PhysRevLett.122.137701)
- [19] A. Tsukazaki, S. Akasaka, K. Nakahara, Y. Ohno, H. Ohno, D. Maryenko, A. Ohtomo, and M. Kawasaki, "Observation of the fractional quantum Hall effect in an oxide," Nature Materials 9[, 889–893 \(2010\).](http://dx.doi.org/10.1038/nmat2874)
- [20] J. Falson, D. Maryenko, B. Friess, D. Zhang, Y. Kozuka, A. Tsukazaki, J. H. Smet, and M. Kawasaki, "Evendenominator fractional quantum Hall physics in ZnO," Nature Physics 11[, 347–351 \(2015\).](http://dx.doi.org/10.1038/nphys3259)
- [21] B. A. Piot, J. Kunc, M. Potemski, D. K. Maude, C. Betthausen, A. Vogl, D. Weiss, G. Karczewski, and T. Wojtowicz, "Fractional quantum Hall effect in CdTe," Physical Review B 82[, 081307\(R\) \(2010\).](http://dx.doi.org/ 10.1103/PhysRevB.82.081307)
- [22] C. Betthausen, P. Giudici, A. Iankilevitch, C. Preis, V. Kolkovsky, M. Wiater, G. Karczewski, B. A. Piot, J. Kunc, M. Potemski, T. Wojtowicz, and D. Weiss, "Fractional quantum Hall effect in a dilute magnetic semiconductor," [Physical Review B](http://dx.doi.org/ 10.1103/PhysRevB.90.115302) 90, 115302 (2014).
- [23] Tomasz M. Kott, Binhui Hu, S. H. Brown, and B. E. Kane, "Valley-degenerate two-dimensional electrons in the lowest Landau level," Phys. Rev. B 89[, 041107\(R\) \(2014\).](http://dx.doi.org/ 10.1103/PhysRevB.89.041107)
- [24] Q. Shi, M. A. Zudov, C. Morrison, and M. Myronov, "Spinless composite fermions in an ultrahigh-quality strained Ge quantum well," Phys. Rev. B 91[, 241303\(R\) \(2015\).](http://dx.doi.org/ 10.1103/PhysRevB.91.241303)
- [25] O. A. Mironov, N. d'Ambrumenil, A. Dobbie, A. V. Suslov, E. Green, and D. R. Leadley, "Fractional Quantum Hall States in a Ge Quantum Well," [Physical Review Letters](http://dx.doi.org/10.1103/PhysRevLett.116.176802) 116, 176802 (2016).
- [26] Meng K. Ma, M. S. Hossain, K. A. VillegasRosales, H. Deng, T. Tschirky, W. Wegscheider, and M. Shayegan, "Observation of fractional quantum Hall effect in an InAs quantum well," Phys. Rev. B 96[, 241301\(R\) \(2017\).](http://dx.doi.org/10.1103/PhysRevB.96.241301)
- [27] S. Komatsu, H. Irie, T. Akiho, T. Nojima, T. Akazaki, and K. Muraki, "Gate tuning of fractional quantum Hall states in an InAs two-dimensional electron gas,"

Phys. Rev. B 105[, 075305 \(2022\).](http://dx.doi.org/ 10.1103/PhysRevB.105.075305)

- [28] Qianhui Shi, En Min Shih, Martin V. Gustafsson, Daniel A. Rhodes, Bumho Kim, Kenji Watanabe, Takashi Taniguchi, Zlatko Papić, James Hone, and Cory R. Dean, "Odd- and even-denominator fractional quantum Hall states in monolayer WSe2," [Nature Nanotechnology](http://dx.doi.org/ 10.1038/s41565-020-0685-6) 15, 569–573 (2020).
- [29] L. Pfeiffer and K. W. West, "The role of MBE in recent quantum Hall effect physics discoveries," Physica E 20[, 57–64 \(2003\).](http://dx.doi.org/ 10.1016/j.physe.2003.09.035)
- [30] V. Umansky, M. Heiblum, Y. Levinson, J. Smet, J. Nübler, and M. Dolev, "MBE growth of ultra-low disorder 2DEG with mobility exceeding 35×10^6 cm²/Vs," J. Cryst. Growth 311[, 1658–1661 \(2009\).](http://dx.doi.org/ 10.1016/j.jcrysgro.2008.09.151)
- [31] Y. Jang Chung, K. A. Villegas Rosales, K. W. Baldwin, P. T. Madathil, K. W. West, M. Shayegan, and L. N. Pfeiffer, "Ultra-high-quality two-dimensional electron systems," Nat. Mater. 20[, 632–637 \(2021\).](http://dx.doi.org/ 10.1038/s41563-021-00942-3)
- [32] E. H. Hwang and S. Das Sarma, "Limit to two-dimensional mobility in modulation-doped GaAs quantum structures: How to achieve a mobility of 100 million," Phys. Rev. B 77[, 235437 \(2008\).](http://dx.doi.org/ 10.1103/PhysRevB.77.235437)
- [33] G. Gamez and K. Muraki, " $v = 5/2$ fractional quantum Hall state in low-mobility electron systems: Different roles of disorder," Phys. Rev. B 88[, 075308 \(2013\).](http://dx.doi.org/10.1103/PhysRevB.88.075308)
- [34] K.-J. Friedland, R. Hey, H. Kostial, R. Klann, and K. Ploog, "New concept for the reduction of impurity scattering in remotely doped GaAs quantum wells," Phys. Rev. Lett. 77[, 4616–4619 \(1996\).](http://dx.doi.org/ 10.1103/PhysRevLett.77.4616)
- [35] Y. J. Chung, K.A.Villegas Rosales, K. W. Baldwin, K. W. West, M. Shayegan, and L. N. Pfeiffer, "Working principles of doping-well structures for high-mobility two-dimensional electron systems," [Physical Review Materials](http://dx.doi.org/10.1103/PhysRevMaterials.4.044003) 4, 044003 (2020).
- [36] M. Sammon, T. Chen, and B. I. Shklovskii, "Excess electron screening of remote donors and mobility in modern GaAs/AlGaAs heterostructures," [Phys. Rev. Materials](http://dx.doi.org/10.1103/PhysRevMaterials.2.104001) 2, 104001 (2018).
- [37] M. Sammon, M. A. Zudov, and B. I. Shklovskii, "Mobility and quantum mobility of modern GaAs/AlGaAs heterostructures," [Phys. Rev. Materials](http://dx.doi.org/10.1103/PhysRevMaterials.2.064604) 2, 064604 (2018).
- [38] T. Akiho and K. Muraki, "Screening effects of superlattice doping on the mobility of GaAs two-dimensional electron system revealed by in situ gate control," [Phys. Rev. Applied](http://dx.doi.org/10.1103/PhysRevApplied.15.024003) 15, 024003 (2021).
- [39] Q. Qian, J. Nakamura, S. Fallahi, G. C. Gardner, J. D. Watson, and M. J. Manfra, "High-temperature resistivity measured at $v = \frac{5}{2}$ as a predictor of the two-dimensional electron gas quality in the $N = 1$ Landau level," Phys. Rev. B 95[, 241304\(R\) \(2017\).](http://dx.doi.org/ 10.1103/PhysRevB.95.241304)
- [40] The divergence at $d_s = 0$ that occurs when applying Eq. (2) to BIs can be avoided by taking into account the finite thickness of the 2DES. Using the wave function $\psi(z)$ of the 2DES, we replaced d_s in Eq. (2) with $\langle d(z) \rangle = \int |z - z'| |\psi(z')|^2 dz'$, which remains finite for all *z*. When the BI concentration (n_{BI}) is constant, the only *z*-dependent factor in the modified Eq. (2) is $\langle d(z) \rangle^{-1}$, with its integration $\beta \equiv \int \langle d(z) \rangle^{-1} dz$ being a dimensionless number. Thus, $\rho_{1/2}$ due to BI scattering is given by $\rho_{1/2} = (\beta / \pi^{1/2}) (n_{\text{BI}} / n_e^{3/2}) (h/e^2)$. For a 30-nm-thick QW with infinite barrier, we have $\beta = 9.4$.
- [41] It is not clear why Eq. (2) tends to overestimate $\rho_{1/2}$ due to RIs when it yields reasonable results when modified for BIs. Possible reasons include spatial correlation among remote ionized impurities and screening due to excess electrons generated by photo illumination [\[33\]](#page-4-6).
- [42] P. T. Coleridge, Z. W. Wasilewski, P. Zawadzki, A. S. Sachrajda, and H. A. Carmona, "Composite-fermion effective masses,"

Phys. Rev. B 52[, R11603–R11606 \(1995\).](http://dx.doi.org/ 10.1103/PhysRevB.52.R11603)

[43] J. H. Smet, D. Weiss, R. H. Blick, G. Lütjering, K. von Klitzing, R. Fleischmann, R. Ketzmerick, T. Geisel, and G. Weimann, "Magnetic focusing of composite fermions through arrays of cavities," Phys. Rev. Lett. 77[, 2272–2275 \(1996\).](http://dx.doi.org/10.1103/PhysRevLett.77.2272)

[44] J. H. Smet, K. von Klitzing, D. Weiss, and W. Wegscheider, "dc transport of composite fermions in weak periodic potentials," Phys. Rev. Lett. 80[, 4538–4541 \(1998\).](http://dx.doi.org/10.1103/PhysRevLett.80.4538)